



These new test clips provide the user with an easy means to connect instrumentation to the fine pitch QFP chip leads.

- Interfaces with high density plastic EIAJ QFP surface mounted chip leads.
- Two stage alignment assures positive connection.
- Gold plated connector pins and contacts assure noise free connections.
- Gold plated .025" square pins provide easy connection with either ribbon cable or jumpers.

Pomona's EIAJ test clips are perfect for use with logic analyzers, for system design, failure analysis, system design and field service testing.

Other clips are available in sizes to fit the most popular EIAJ and JEDEC chips now in use.

Pomona also offers a test clip to fit the most commonly found variations on the EIAJ specifications.

All dimensions are in inches. Tolerances (except noted): .xx = ±.02" (.51 mm), .xxx = ±.005" (.127 mm).

All specifications are to the latest revisions. Specifications are subject to change without notice.

Registered trademarks are the property of their respective companies. Made in USA